

● **General Description**

The TF012N04NGC combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

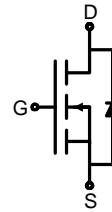
● **Features**

- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

● **Application**

- MB/VGA Vcore
- SMPS 2<sup>nd</sup> Synchronous Rectifier
- POL application
- BLDC Motor driver

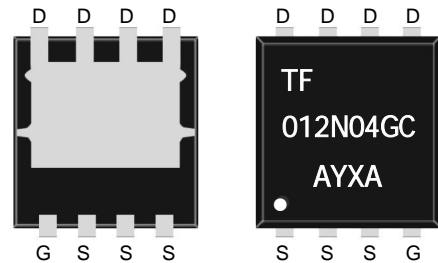
● **Product Summary**



$V_{DS} = 40V$   $I_D = 214A$

$R_{DS(ON)(10V\ typ)} = 1.1m\Omega$

$R_{DS(ON)(4.5V\ typ)} = 1.7m\Omega$



**PDFN5x6-8L-Clip**

● **Ordering Information:**

Part NO.	TF012N04NGC
Marking 1	012N04GC : TF012N04NGC
Marking 2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

● **Absolute Maximum Ratings** ( $T_C = 25^\circ C$ )

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	214	A
	$I_D @ T_C = 75^\circ C$	150	A
	$I_D @ T_C = 100^\circ C$	135	A
Pulsed Drain Current ①	$I_{DM}$	856	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	104	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	1.5	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$

Note: ① Pulse Test : Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$  ;



Shenzhen Tuofeng Semiconductor Technology Co., Ltd  
**N-CHANNEL ENHANCEMENT MODE POWER MOSFET**

SGT MOS、低内阻、低结电容开关损耗小

**TF012N04NGC**

Single Pulse Avalanche Energy	$E_{AS}$	490			mJ	
Avalanche Current(L=0.1mH)	$I_{AS} I_{AR}$	50			A	
<b>●Thermal resistance</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Min.</b>	<b>Typ.</b>	<b>Max.</b>	<b>Unit</b>	
Thermal resistance, junction - case	$R_{thJC}$	-	-	1.2	° C/W	
Thermal resistance, junction - ambient	$R_{thJA}$	-	-	45	° C/W	
Soldering temperature, wave soldering for 8s	$T_{sold}$	-	-	265	° C	
<b>●Electronic Characteristics(<math>T_a = 25^\circ C</math>)</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.2	1.7	2.4	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = 45V, V_{GS} = 0V$			1.0	$\mu A$
Gate- Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 20A$		1.1	1.4	m $\Omega$
		$V_{GS} = 4.5V, I_D = 15A$		1.7	2.2	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = 10V, I_D = 20A$		56		S
Source-drain voltage	$V_{SD}$	$I_S = 20A$			1.20	V
<b>●Electronic Characteristics(<math>T_a = 25^\circ C</math>)</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Input capacitance	$C_{iss}$	$V_{ds} = 20V, V_{gs} = 0V$ $f = 1MHz$	-	3008	-	pF
Output capacitance	$C_{oss}$		-	1635	-	
Reverse transfer capacitance	$C_{rss}$		-	68.0	-	
<b>●Gate Charge characteristics(<math>T_a = 25^\circ C</math>)</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Gate Resistance	$R_g$	$f = 1MHz$		0.9		$\Omega$
Total gate charge	$Q_g$	$V_{DD} = 20V$ $I_D = 20A$ $V_{GS} = 10V$	-	44.0	-	nC
Gate - Source charge	$Q_{gs}$		-	9.50	-	
Gate - Drain charge	$Q_{gd}$		-	6.70	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS} = 10V, V_{DS} = 20V$ $R_G = 3.0\Omega, I = 20A$		4.60		ns
Turn-ON Rise time	$t_r$			9.60		ns
Turn-Off Delay time	$t_{D(off)}$			31.0		ns
Turn-Off Fall time	$t_f$			14.0		ns



Typical Electrical and Thermal Characteristics

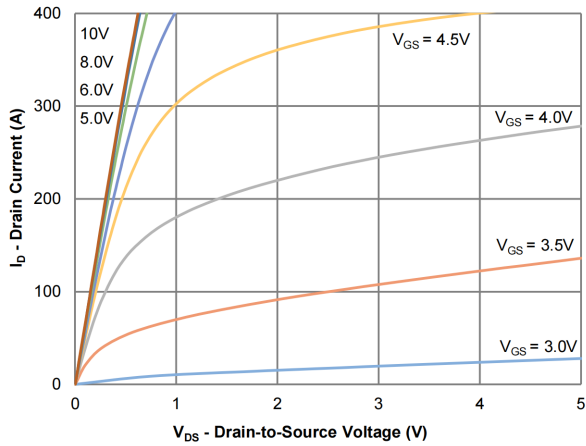


Figure 1: Output Characteristics

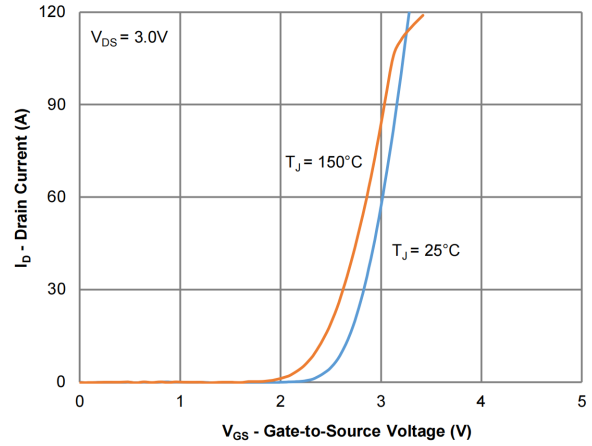


Figure 2: Transfer Characteristics

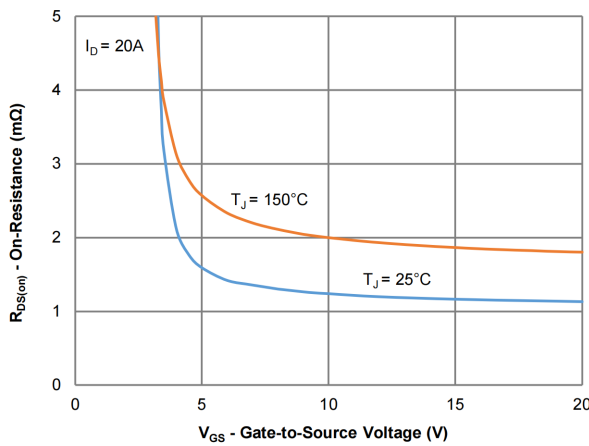


Figure 3: On-Resistance vs. Gate-Source Voltage

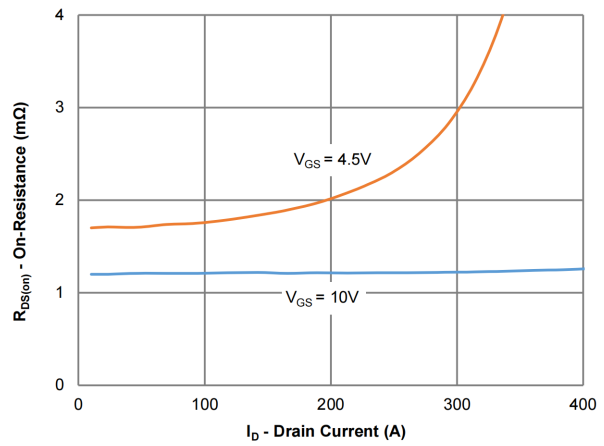


Figure 4: On-Resistance vs. Gate-Source Voltage

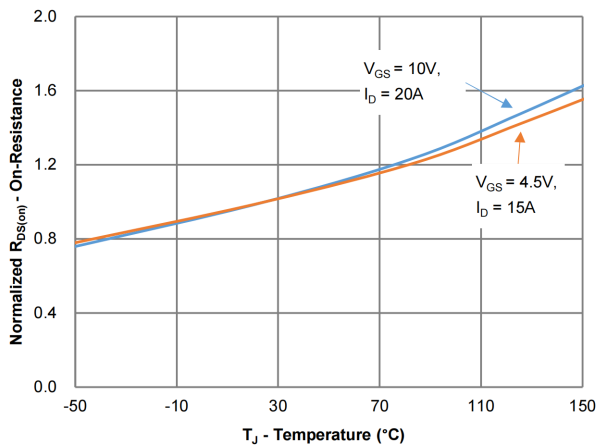


Figure 5: On-Resistance vs. Junction Temperature

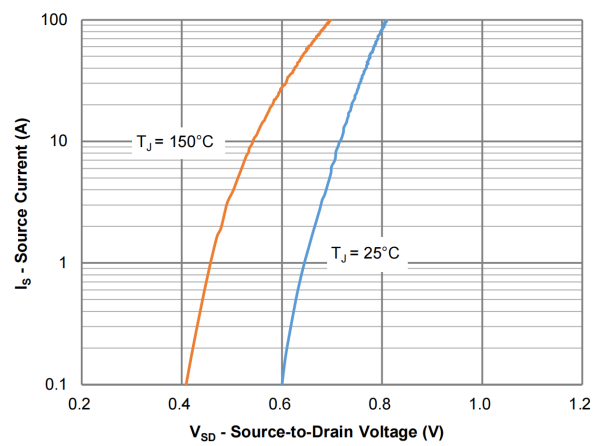


Figure 6: Source-Drain Diode Forward Voltage

Typical Electrical and Thermal Characteristics

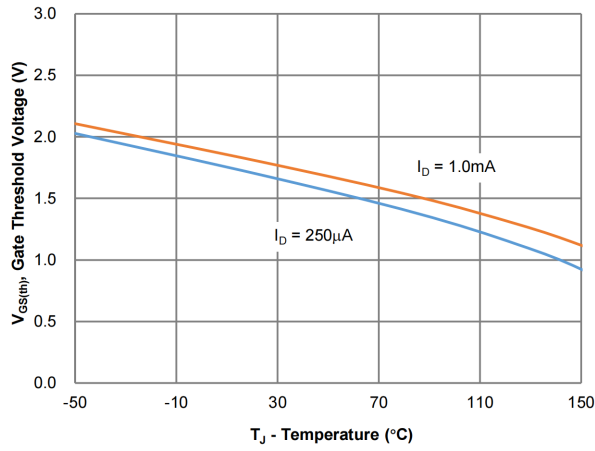


Figure 7: Gate Threshold Variation vs. Junction Temperature

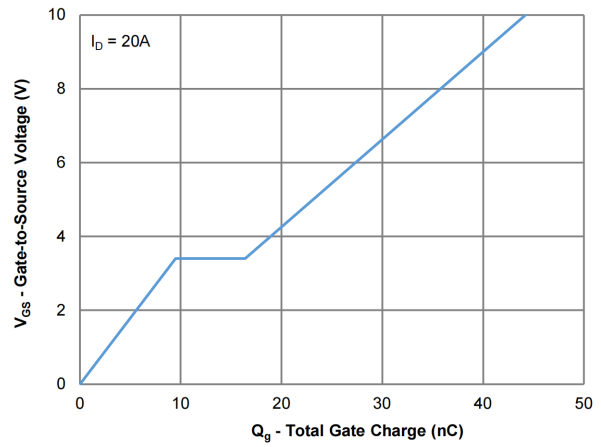


Figure 8: Gate Charge Characteristics

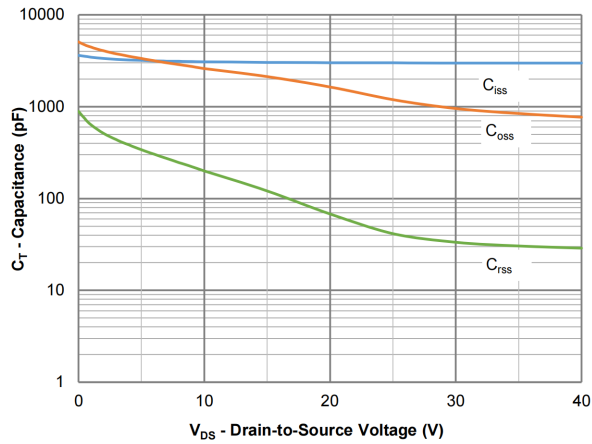


Figure 9: Capacitance Characteristics

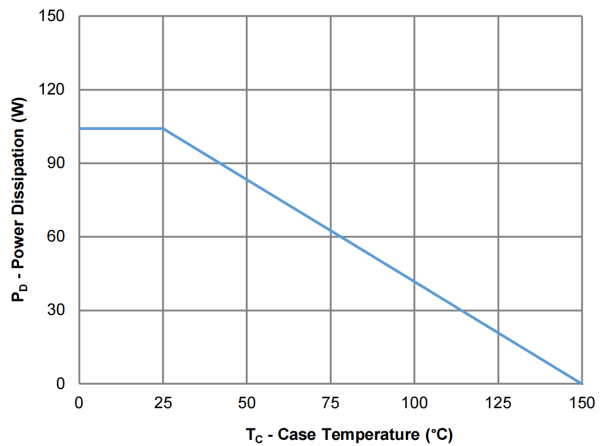


Figure 10: Power Derating

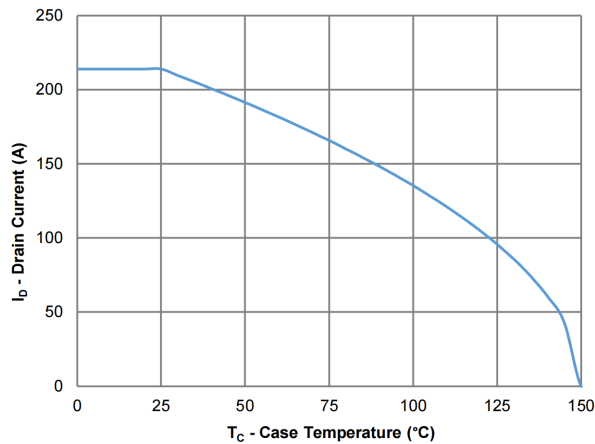


Figure 11: Current Derating

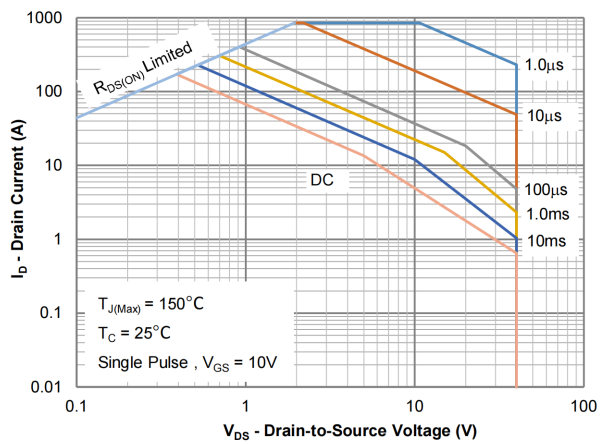


Figure 12: Safe Operating Area

Typical Electrical and Thermal Characteristics

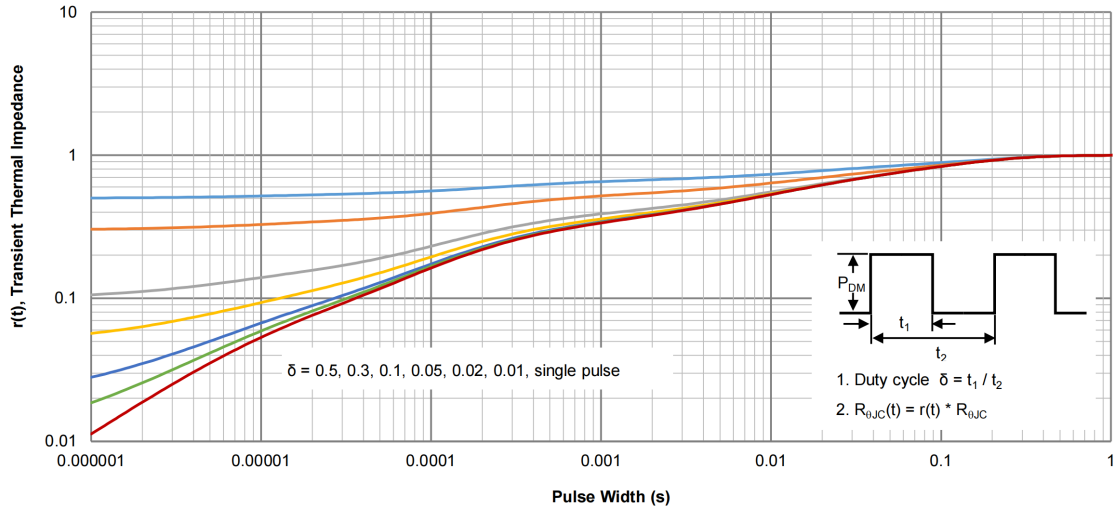
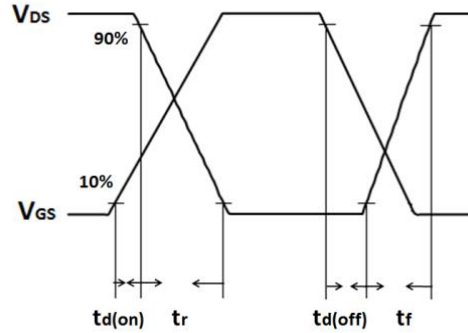
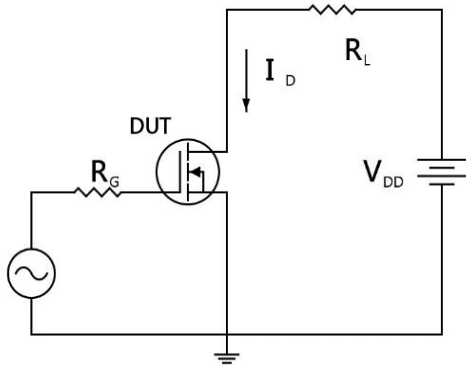
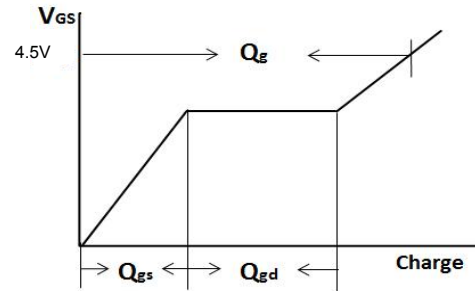
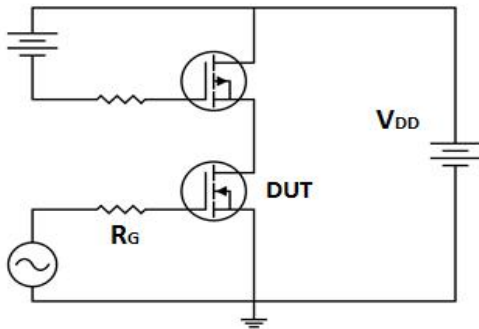


Figure 13: Normalized Maximum Transient Thermal Impedance

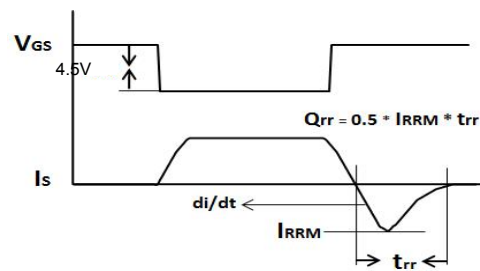
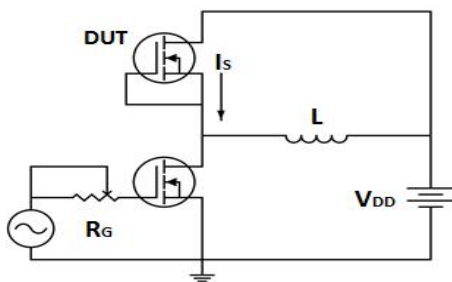
**Resistive switching time test circuit & waveforms**



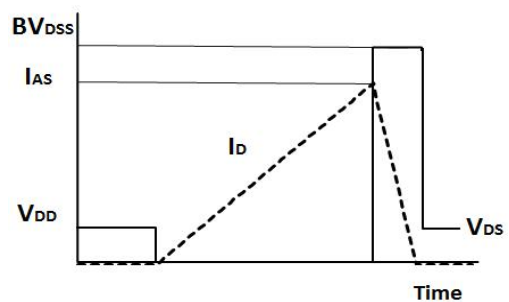
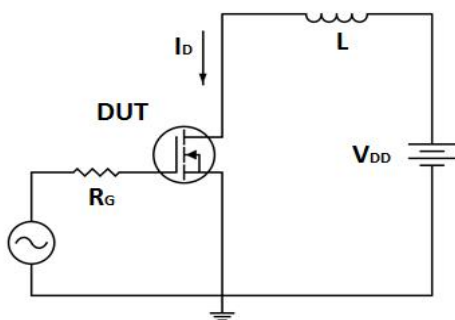
**Gate charge test circuit & waveforms**



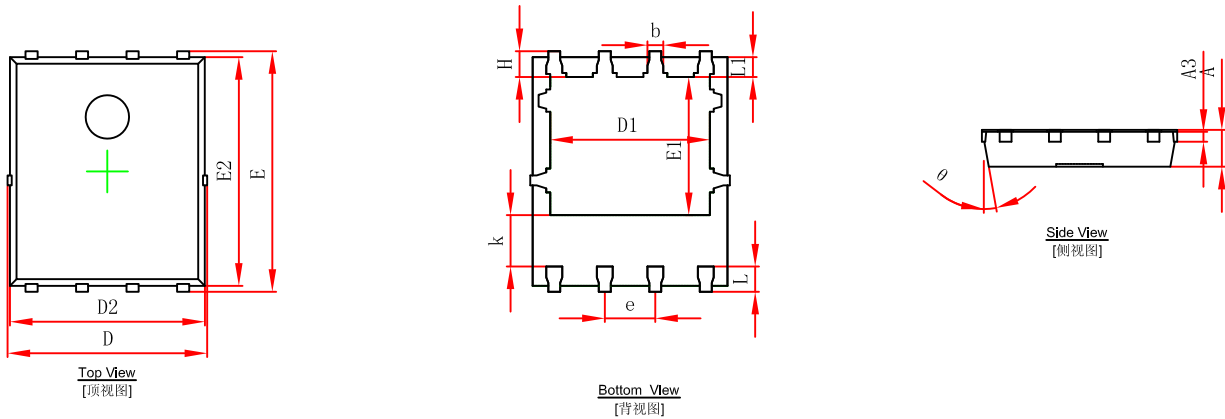
**Peak diode recovery dv/dt circuit & waveforms**



**Unclamped inductive switching test circuit & waveforms**

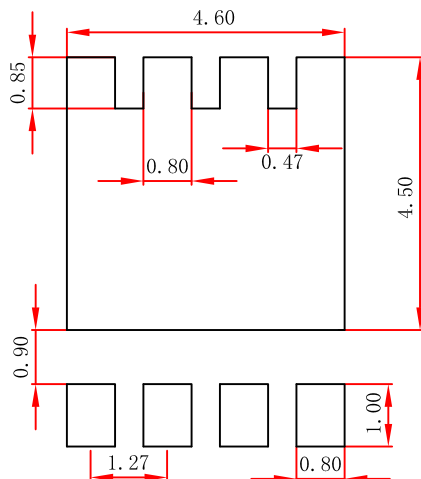


**PDFN5x6-8L Package Outline Dimensions**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

**PDFN5x6-8L Suggested Pad Layout**



Note:  
 1. Controlling dimension: in millimeters.  
 2. General tolerance: ±0.05mm.  
 3. The pad layout is for reference purposes only.